

<b>Form PTO 1449</b>  <b>U.S. Department of Commerce</b> <b>Patent and Trademark Office</b>  Information Disclosure Statement by Applicant	<b>ATTY. DOCKET NUMBER:</b>  <b>11330-1</b>	<b>SERIAL NUMBER:</b>  
	<b>APPLICANT: VINCENT DETALLE ET AL</b>	
	<b>FILING DATE: HERewith</b>	<b>GROUP:</b>

11/16/01  
 09/987819  
 10971 U.S. PTO

**U.S. Patent Documents**

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCL ASS	FILING DATE IF APPROPRIATE
	AA	5,781,289	July 14, 1998	Sabsabi <sup>ET AL</sup> and Bucciore			
SAT	AB	6,259,530	July 10, 2001	Monsallut			
SAT	AC	<del>4,627,731</del>	<del>December 9, 1986</del>	<del>Waters and Fernald</del>	<b>ALREADY CITED</b>		

**Foreign Patent Documents**

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL							
	AM							

**Other Documents (Including Author, Title, Date Pertinent Pages, Etc.)**

SAT	AR	Günther et al., Spectrochim. Acta Part B, vol. 54, 1999, p. 381
↑	AS	Kanický et al., Fresenius J. Anal. Chem., vol. 366, 2000, p. 228)
	AT	Wong et al., SPIE, vol. 2390, 1995, p. 68
	AU	Kay et al., Int. J. Impact Engng., vol. 19, 1997, p. 739
	AV	Borisov et al., Spectrochim. Acta Part B, vol. 55, 2000, p. 1693
	AW	Lausten and Balling, Appl. Phys. Lett., vol. 79, 2001, p. 884
	AX	Uebbing et al., Spectrochim. Acta Part B, vol. 47, 1992, p. 611
↓ SAT	AY	Rao and Jackson, Meas. Sci. Technol., vol. 7, 1996, p. 981

EXAMINER <b>S.D. Turner</b>	DATE CONSIDERED <b>3-10-04</b>
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**EXAMINER:** Initial if citation is considered, whether or not citation is in conformance with MPEP 609; draw a line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant

Substitute form for form 1449A & 1449B/PTO		Complete if Known	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (use as many sheets as necessary)		Application No.	09/987,819
		Filing Date	November 16, 2001
		First Named Inventor	Datalle et al.
		Group Art Unit	2877
		Examiner Name	Philip Natividad
Sheet 1 of 1	Attorney Docket No.	11330-01 US	



U.S. PATENT DOCUMENTS						
Examiner Initials*	Cite No. <sup>1</sup>	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code <sup>2</sup> (if known)			
SAT		4,627,731		Waters et al.	12-09-1986	
SAT		5,720,894		Neev et al.	11-24-1998	
SAT		<del>0,259,530</del>		<del>Monsallut</del>	<del>07-10-2001</del>	<del>PREVIOUSLY CITED</del>

FOREIGN PATENT DOCUMENTS								
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear	T <sup>6</sup>
		Office <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>5</sup> (if known)				

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in capital letters), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>6</sup>
SAT		Anderson et al., "Depth Profile Studies Using Laser-Induced Plasma Emission Spectrometry", 1369 Applied Spectroscopy, XP000508969, vol. 49, no. 6, June 1995, Society for Applied Spectroscopy, Baltimore, USA	
SAT		Borisov et al., "Laser Ablation Inductively Coupled Plasma Mass Spectrometry of Pressed Pellet Surrogates for Pu Materials Disposition", Applied Spectroscopy, XP-001125028, vo. 55, no. 10, 2001, Society for Applied Spectroscopy, Baltimore USA	
SAT		Wong et al., "Surface Characterization of Laser Ablated Hard Tissue: A Comparison of Scanning White Light Interferometry and Electron Microscopy", Proceedings of the SPIE, XP009003998, vol. 2390, pp. 68-75, 1995, SPIE Bellingham, VA USA	

Examiner Signature	J. A. TUANGA	Date Considered	3-10-04
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1 Unique citation designation number. 2 See attached Kinds of U.S. Patent Documents. 3 Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). 4 For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. 5 Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. 6 Applicant is to place a check mark here if English language Translation is attached.